



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

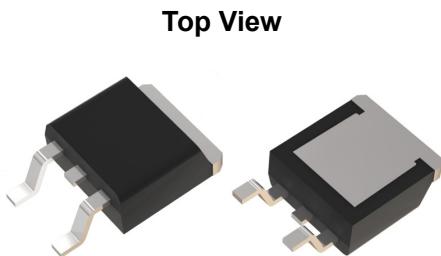
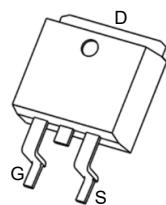
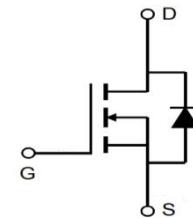
N - CHANNEL ENHANCEMENT MODE POWER MOSFET**TF120N10DG****Features**

- $V_{DS} = 100V$, $I_D = 120A$
- $R_{DS(ON)}=3.4m\Omega$ (typ.) @ $V_{GS}=10V$
- $R_{DS(ON)}=4.9m\Omega$ (typ.) @ $V_{GS}=4.5V$

- Low $R_{DS(ON)}$
- Good stability and uniformity with high EAS High Current Capability
- Excellent package for good heat dissipation
- Fully characterized avalanche voltage and current

Application

- Power management
- Hard switched and high frequency circuits
- Uninterruptible power supply

**Package****Top View****Schematic diagram****Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
TF120N10DG	TF120N10DG	TO-263	-	-	-

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise specified)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C=25^\circ C$	I_D	120	A
	$T_C=100^\circ C$		72	
Pulsed Drain Current ¹		I_{DM}	480	A
Single Pulse Avalanche Energy ²		EAS	300	mJ
Total Power Dissipation	$T_C=25^\circ C$	P_D	200	W
Operating Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C
Thermal Resistance from Junction-to-Ambient ³		R_{JA}	35	°C/W
Thermal Resistance from Junction-to-Case		R_{JC}	0.5	°C/W



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Electrical Characteristics ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100	-	-	V
Gate-body Leakage current	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 90\text{V}, V_{\text{GS}} = 0\text{V}$	-	-	1	μA
	I_{DSS}		-	-	100	
Gate-Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.2	1.7	2.5	V
Drain-Source on-Resistance ⁴	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 20\text{A}$	-	3.4	4.2	$\text{m}\Omega$
		$V_{\text{GS}} = 4.5\text{V}, I_D = 20\text{A}$	-	4.9	6.0	
Dynamic Characteristics⁵						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 50\text{V}, V_{\text{GS}} = 0\text{V}, f = 1\text{MHz}$	-	6095	-	pF
Output Capacitance	C_{oss}		-	722	-	
Reverse Transfer Capacitance	C_{rss}		-	17	-	
Gate Resistance	R_g	$f = 1\text{MHz}$	-	1.3	-	Ω
Switching Characteristics⁵						
Total Gate Charge	Q_g	$V_{\text{GS}} = 10\text{V}, V_{\text{DS}} = 50\text{V}, I_D = 20\text{A}$	-	111.2	-	nC
Gate-Source Charge	Q_{gs}		-	17.5	-	
Gate-Drain Charge	Q_{gd}		-	30.2	-	
Turn-on Delay Time	$t_{d(\text{on})}$	$V_{\text{GS}} = 10\text{V}, V_{\text{DD}} = 50\text{V}, R_G = 3\Omega, I_D = 20\text{A}$	-	22.2	-	ns
Rise Time	t_r		-	37.8	-	
Turn-off Delay Time	$t_{d(\text{off})}$		-	95.3	-	
Fall Time	t_f		-	35.6	-	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20\text{A}, di/dt = 100\text{A}/\mu\text{s}$	-	59.4	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	91.8	-	nC
Drain-Source Body Diode Characteristics						
Diode Forward Voltage ⁴	V_{SD}	$I_S = 20\text{A}, V_{\text{GS}} = 0\text{V}$	-	-	1.2	V
Continuous Source Current	I_S	-	-	-	120	A

Notes:

- Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})} = 150^\circ\text{C}$.
- The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=35\text{V}, V_{\text{GS}}=10\text{V}, L=0.4\text{mH}, I_{\text{AS}}=40\text{A}$.
- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
- The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- This value is guaranteed by design hence it is not included in the production test.

Typical Characteristics

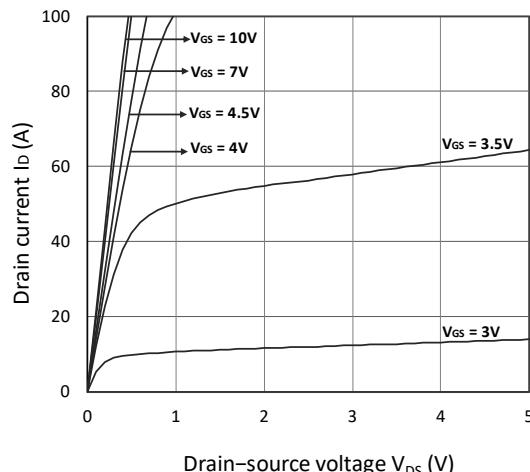


Figure 1. Output Characteristics

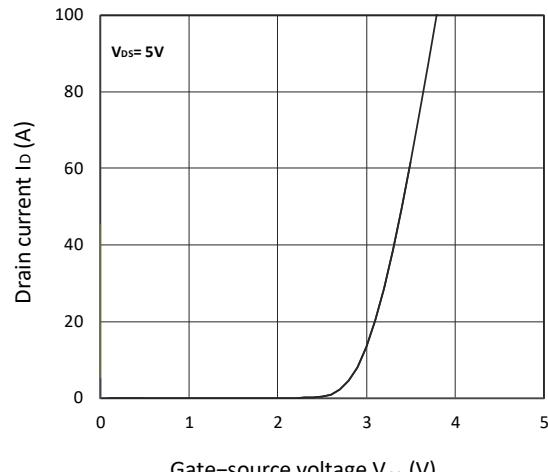


Figure 2. Transfer Characteristics

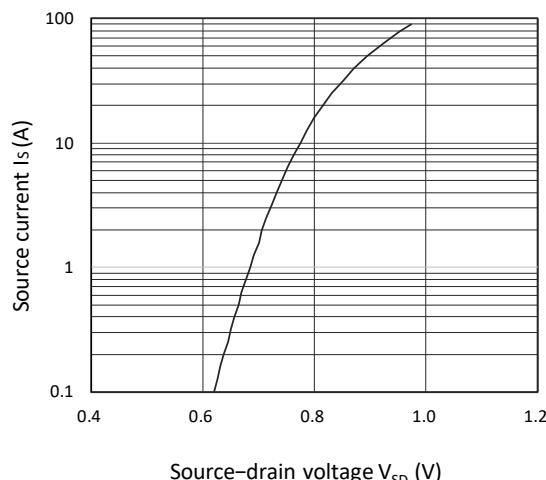


Figure 3. Forward Characteristics of Reverse

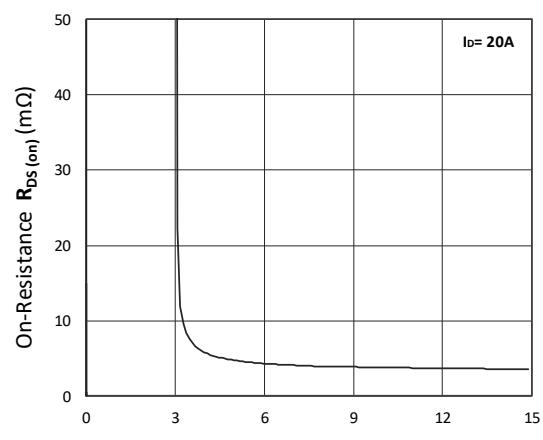


Figure 4. $R_{DS(on)}$ vs. V_{GS}

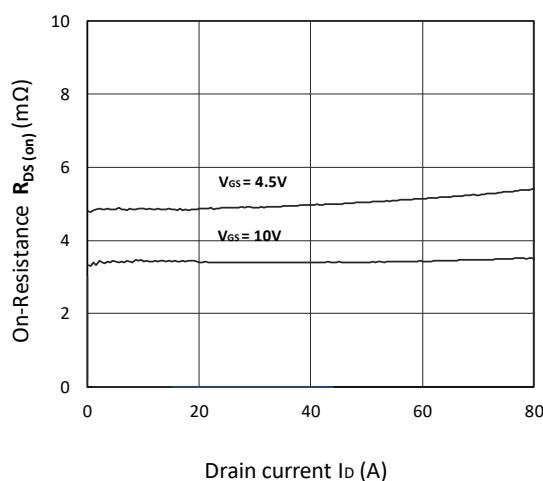


Figure 5. $R_{DS(on)}$ vs. I_D

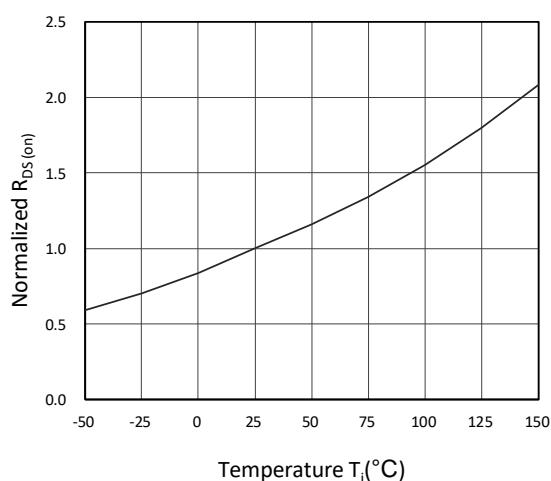


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

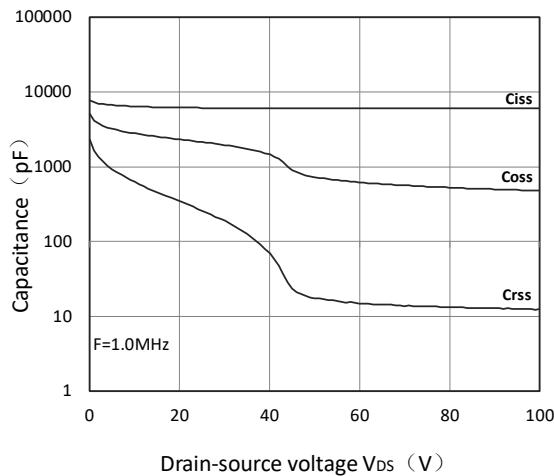


Figure 7. Capacitance Characteristics

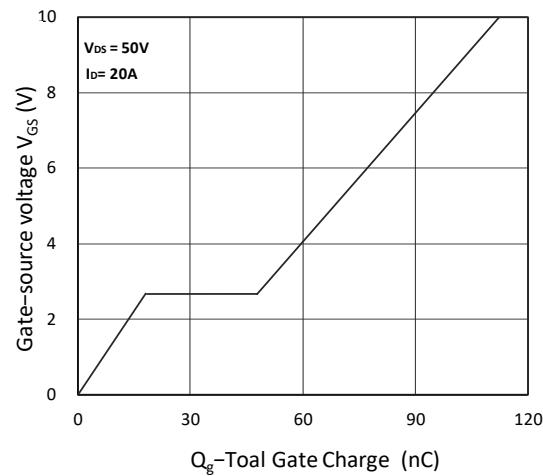


Figure 8. Gate Charge Characteristics

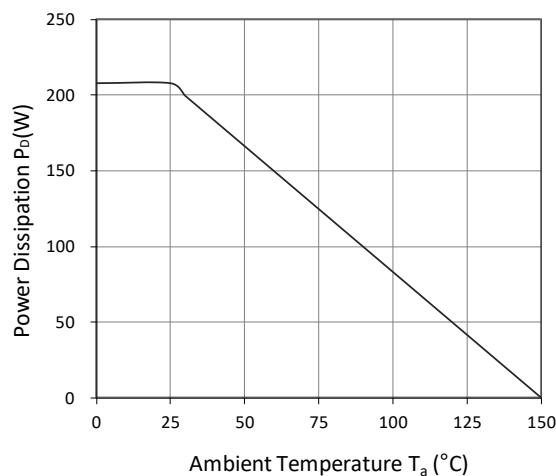


Figure 9. Power Dissipation

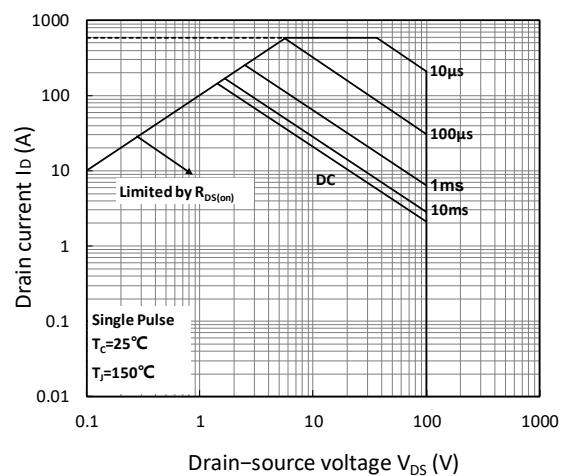


Figure 10. Safe Operating Area

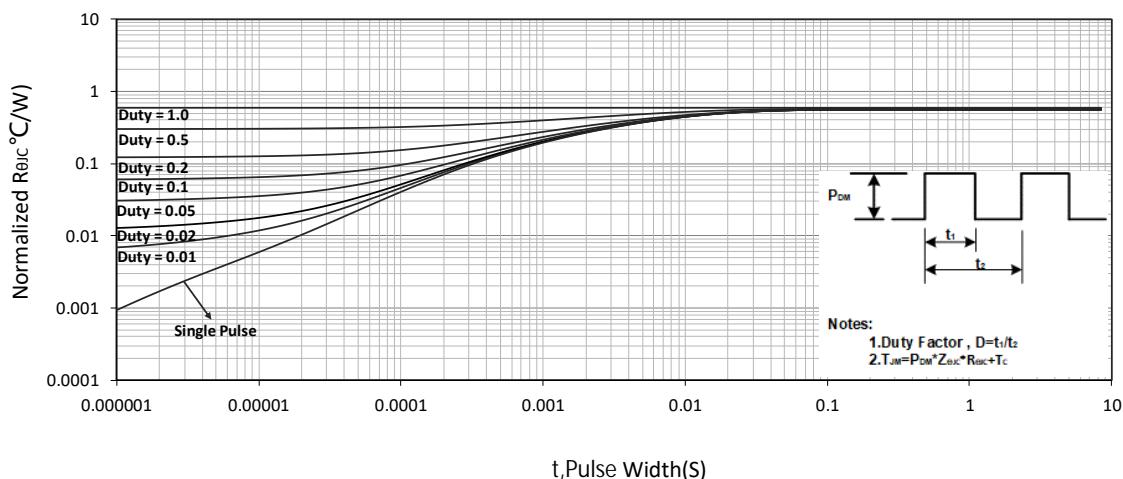


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

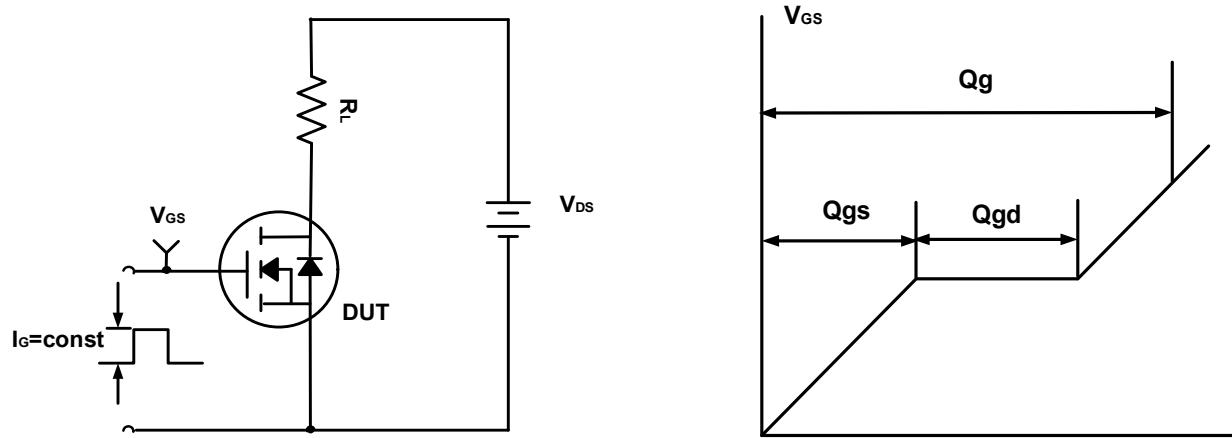


Figure A. Gate Charge Test Circuit & Waveforms

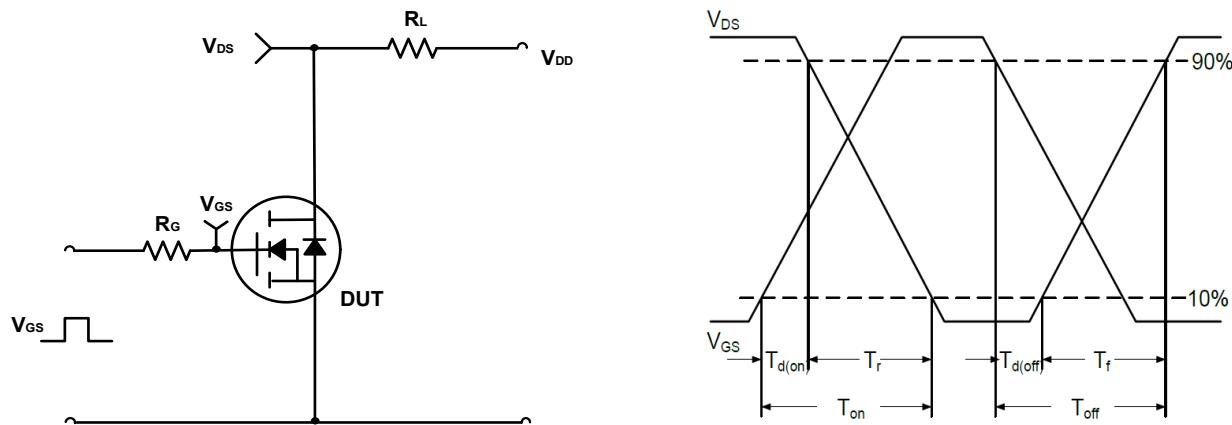


Figure B. Switching Test Circuit & Waveforms

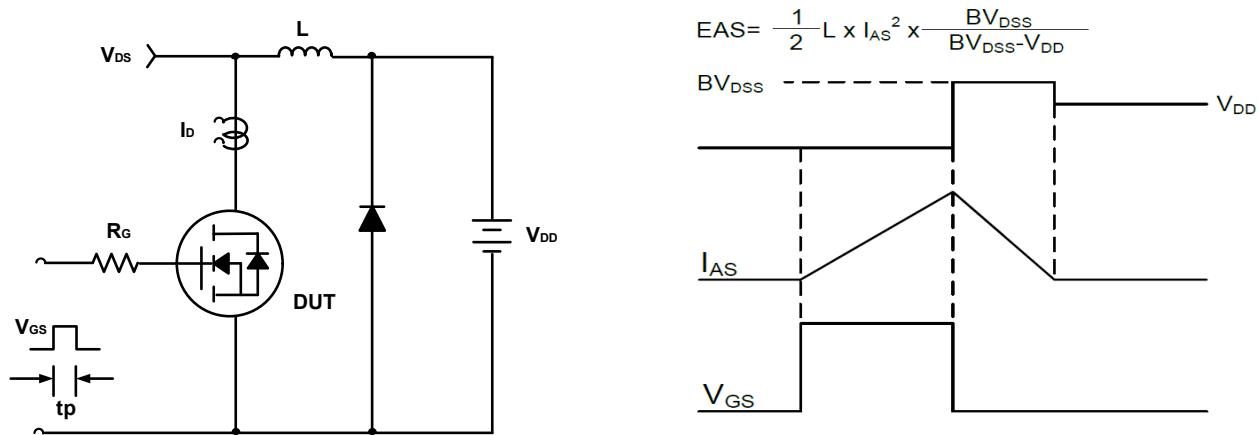


Figure C. Unclamped Inductive Switching Circuit & Waveforms

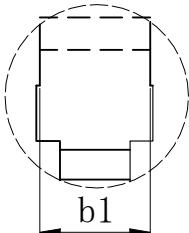
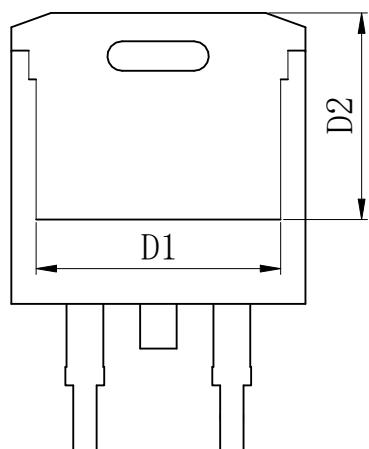
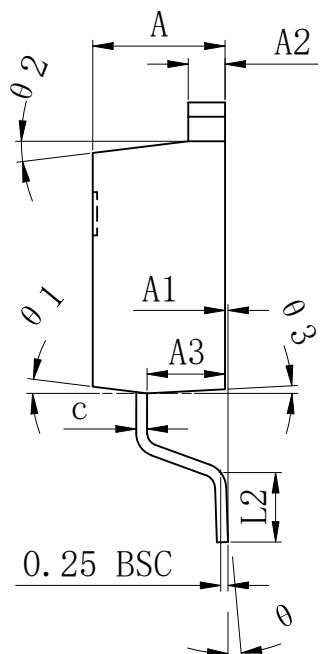
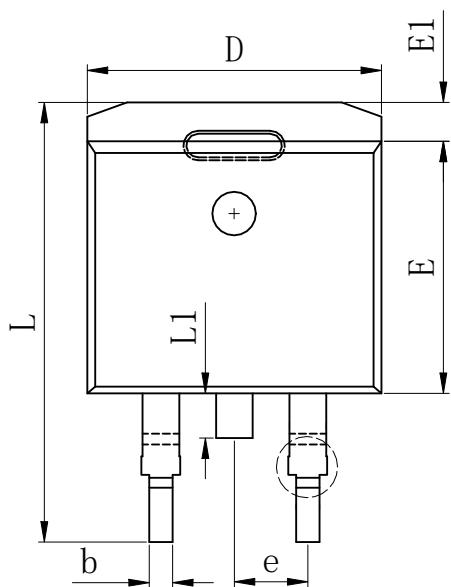


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TF120N10DG

Mechanical Dimensions for TO-2LL



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	4.370	4.570	4.770
A1	0.000		0.250
A2	1.220	1.270	1.420
A3	2.490	2.690	2.890
b	0.700	0.810	0.960
b1	1.170	1.270	1.470
c	0.300	0.380	0.530
D	9.860	10.160	10.360
D1	8.400 REF		
D2	7.073 REF		
E	8.500	8.700	8.900
E1	1.070	1.270	1.470
e	2.540 TYP		
L	14.700	15.100	15.500
L1	1.400	1.550	1.700
L2	2.000	2.300	2.600
θ	0°		9°
θ 1	7° TYP		
θ 2	7° TYP		
θ 3	3° TYP		